

## Description

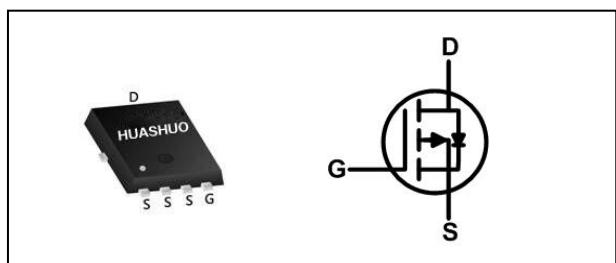
The HSBB60P02 is the high cell density trenched P-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The HSBB60P02 meet the RoHS and Green Product requirement with full function reliability approved.

- Super Low Gate Charge
- Green Device Available
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

## Product Summary

V <sub>DS</sub>	-20	V
R <sub>DSON,typ</sub>	4.3	mΩ
I <sub>D</sub>	-60	A

## PRPAK3x3 Pin Configuration



## Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-20	V
V <sub>GS</sub>	Gate-Source Voltage	± 12	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ -4.5V <sup>1</sup>	-60	A
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ -4.5V <sup>1</sup>	-40	A
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	-255	A
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>3</sup>	31	W
P <sub>D</sub> @T <sub>C</sub> =100°C	Total Power Dissipation <sup>3</sup>	12	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Max.	Unit
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>	70	°C/W
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup> (t ≤ 10s)	35	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	4	°C/W



**Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{I}_D=-250\mu\text{A}$	-20	---	---	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$\text{V}_{\text{GS}}=-4.5\text{V}$ , $\text{I}_D=-20\text{A}$	---	4.3	5.5	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=-2.5\text{V}$ , $\text{I}_D=-20\text{A}$	---	6.5	8.5	
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{GS}}=\text{V}_{\text{DS}}$ , $\text{I}_D=-250\mu\text{A}$	-0.5	---	-1.0	V
$\text{I}_{\text{DSS}}$	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=-20\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $T_J=25^{\circ}\text{C}$	---	---	1	$\mu\text{A}$
$\text{I}_{\text{GSS}}$	Gate-Source Leakage Current	$\text{V}_{\text{GS}}=\pm 12\text{V}$ , $\text{V}_{\text{DS}}=0\text{V}$	---	---	$\pm 100$	nA
$\text{g}_{\text{fs}}$	Forward Transconductance	$\text{V}_{\text{DS}}=-5\text{V}$ , $\text{I}_D=-10\text{A}$	---	55	---	S
$\text{R}_g$	Gate resistance	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{V}_{\text{DS}}=0\text{V}$ , $f=1.0\text{MHz}$	---	4.5	---	$\Omega$
$\text{Q}_g$	Total Gate Charge (-4.5V)	$\text{V}_{\text{DS}}=-10\text{V}$ , $\text{V}_{\text{GS}}=-4.5\text{V}$ , $\text{I}_D=-20\text{A}$	---	41	---	nC
$\text{Q}_{\text{gs}}$	Gate-Source Charge		---	9.9	---	
$\text{Q}_{\text{gd}}$	Gate-Drain Charge		---	14	---	
$\text{T}_{\text{d(on)}}$	Turn-On Delay Time	$\text{V}_{\text{DD}}=-10\text{V}$ , $\text{V}_{\text{GS}}=-4.5\text{V}$ , $\text{R}_G=3.3\Omega$ , $\text{I}_D=-20\text{A}$	---	15	---	ns
$\text{T}_r$	Rise Time		---	7	---	
$\text{T}_{\text{d(off)}}$	Turn-Off Delay Time		---	222	---	
$\text{T}_f$	Fall Time		---	99	---	
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{DS}}=-10\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	4883	---	pF
$\text{C}_{\text{oss}}$	Output Capacitance		---	689	---	
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance		---	611	---	

**Diode Characteristics**

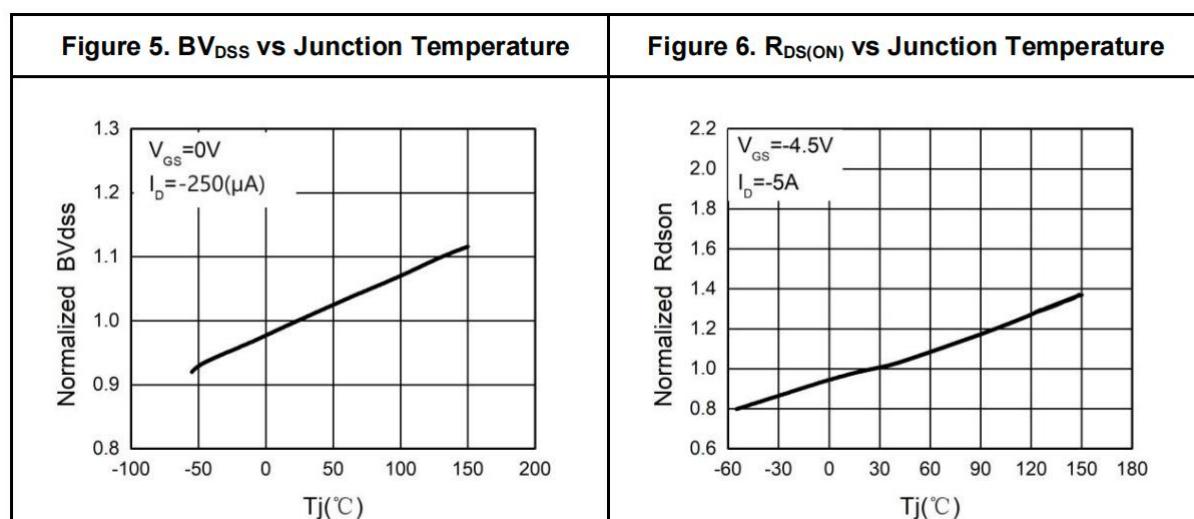
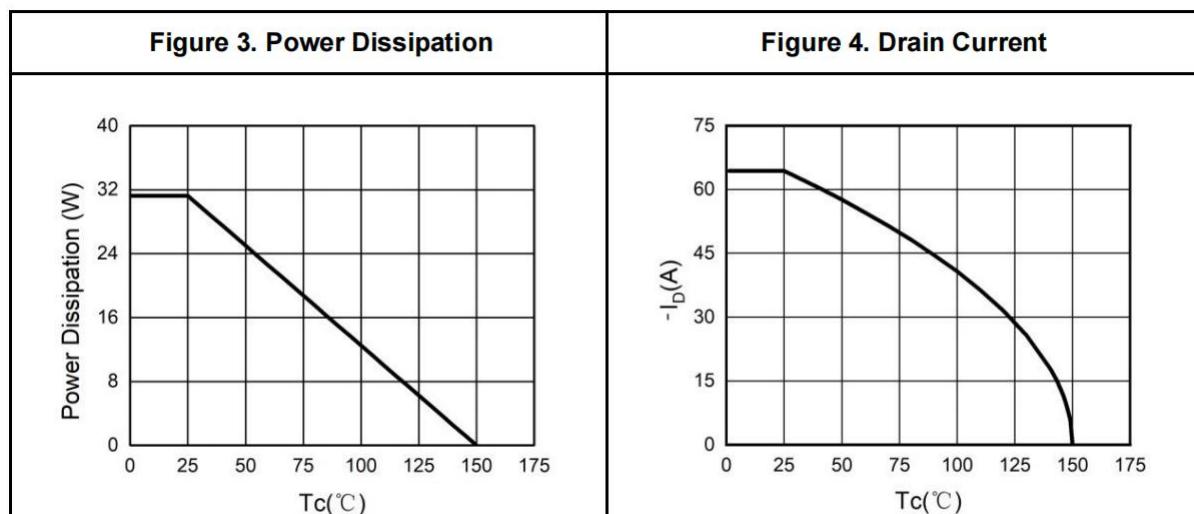
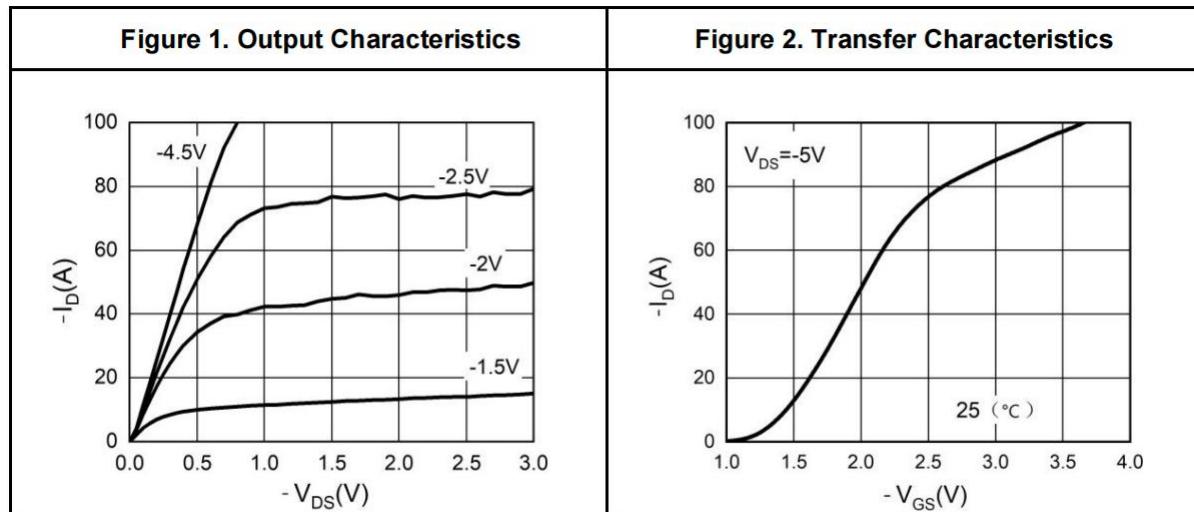
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{I}_s$	Continuous Source Current <sup>1,4</sup>	$\text{V}_G=\text{V}_D=0\text{V}$ , Force Current	---	---	-60	A
$\text{V}_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{I}_s=-1\text{A}$ , $T_J=25^{\circ}\text{C}$	---	---	-1.2	V
$\text{t}_{\text{rr}}$	Reverse Recovery Time	$\text{I}_{\text{F}}=-10\text{A}$ , $d\text{I}/dt=100\text{A}/\mu\text{s}$ , $T_J=25^{\circ}\text{C}$	---	25	---	nS
$\text{Q}_{\text{rr}}$	Reverse Recovery Charge		---	11	---	nC

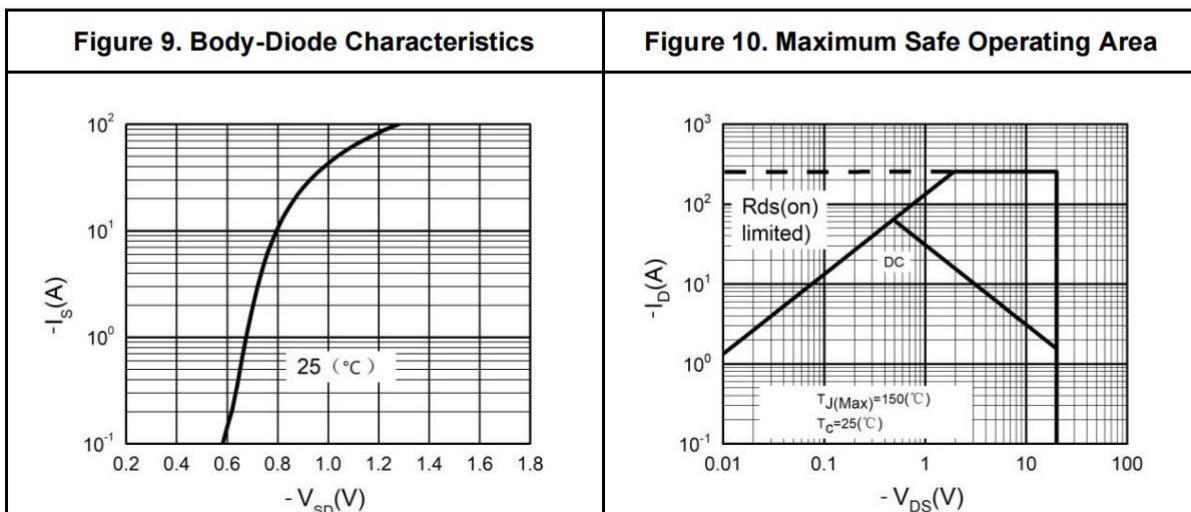
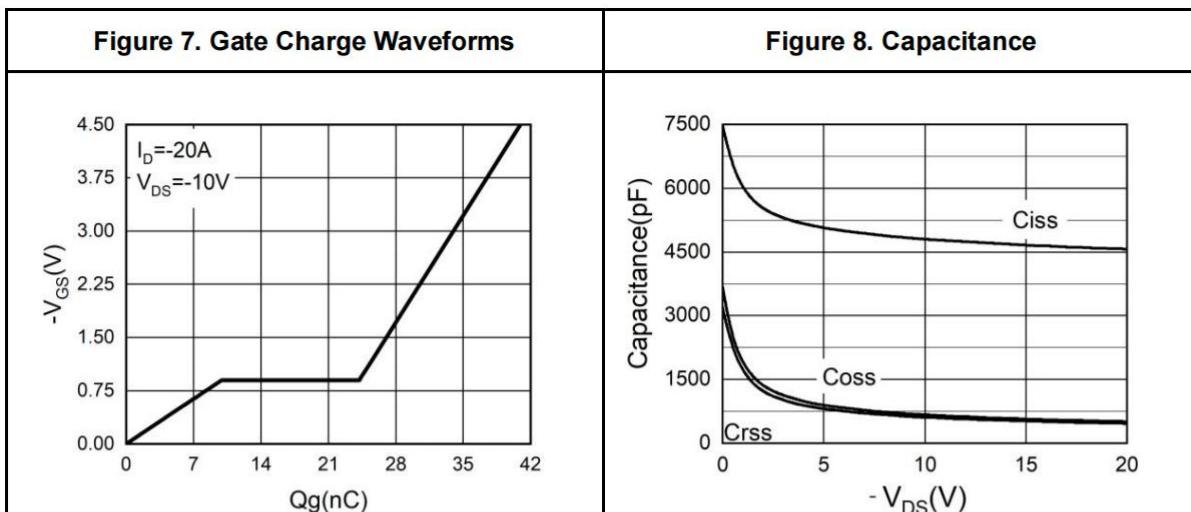
Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
- 3.The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature
- 4.The data is theoretically the same as  $\text{I}_D$  and  $\text{I}_{\text{DM}}$  , in real applications , should be limited by total power dissipation.



### Typical Characteristics







**HUASHUO**  
SEMICONDUCTOR

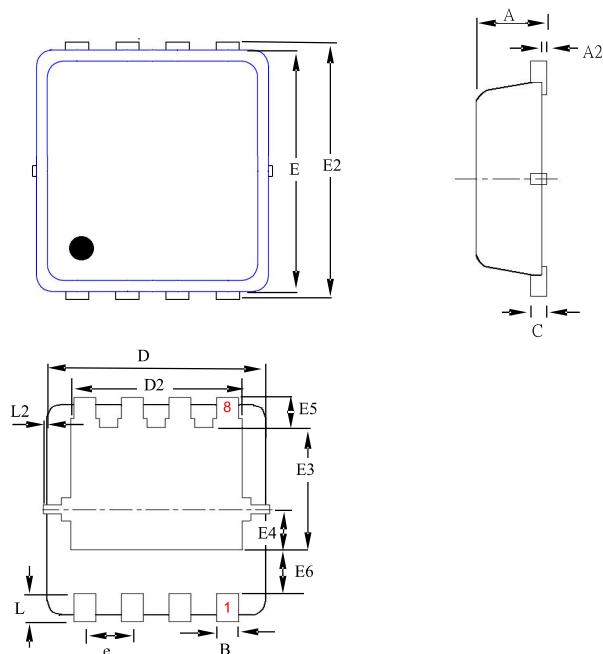
**HSBB60P02**

P-Ch 20V Fast Switching MOSFETs

## Ordering Information

Part Number	Package code	Packaging
HSBB60P02	PRPAK3*3	3000/Tape&Reel

**PRPAK 3\*3(E) Single Outline**



SYMBOLS	MILLIMETERS			INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.80	0.90	0.028	0.031	0.035
A2	0.00	—	0.05	0.000	—	0.002
B	0.24	0.30	0.35	0.009	0.012	0.014
C	0.10	0.15	0.25	0.004	0.006	0.010
D	2.90	3.00	3.20	0.114	0.118	0.126
D2	2.15	2.35	2.59	0.085	0.093	0.102
E	2.90	3.00	3.12	0.114	0.118	0.123
E2	3.05	3.20	3.45	0.120	0.126	0.136
E3	1.55	1.75	1.95	0.061	0.069	0.077
E4	0.48	0.58	0.68	0.019	0.023	0.027
E5	0.28	0.43	0.58	0.011	0.017	0.023
E6	0.43	0.63	0.87	0.017	0.025	0.034
L	0.30	0.40	0.50	0.012	0.016	0.020
L2	0.00	—	0.10	0.000	—	0.004
e	—	0.65	--	--	0.026	--